

PCN# : P178A
Issue Date : 04/08/2011

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

Implementation of change:

Expected First Shipment Date for Changed Product : 02/11/2011

Expected First Date Code of Changed Product :4311

Last Date for Shipment of Unchanged Product : 02/11/2011

Description of Change (From) :

The products listed below have been fully qualified are being sourced from the Mountain Top, PA wafer fab facility.

Description of Change (To) :

This PCN is adding Bucheon South Korea as an alternate wafer fab facility from which product can be sourced. The identified products have been fully qualified in the Bucheon fab and match performance to the products from the Mountain Top fab. In addition to making the Bucheon fab a sourcing option for these products, the Mountain Top fab will remain a valid source for these products.

Reason for Change:

The change to add Bucheon as an alternate fab site is being implemented to increase manufacturing flexibility.

Affected Product(s):

FDH038AN08A1	HUF76639S3ST	HUF75645S3ST
FDM3622	FDP038AN06A0	FDP054N10
FDB2572	FDB050AN06A0	FDB045AN08A0_SN00005
FDB035AN06A0_SN00015	FDP3632	RFD12N06RLESM9A
FDP3651U	FDI3632	HUF75545S3ST_F101
HUF75542P3	FDP047N08_F102	FDI040N06
PCF2532W_R4800	HUF75639P3_F102	FDB088N08
FDPF3860TYDTU	FDD13AN06A0	FDMC15N06
FDH3632	HUF76423P3	FDB5800
HUF76439S3ST	HUF76407D3ST	FDP040N06
FDPF680N10T	RFD3055LESM9A	FDMS2572
FDB3632	HUF75545S3ST	HUF76429S3ST
FDMS2672	FDP047AN08A0_F102	HUF75645P3
FDB2710	FDI030N06	FDI038AN06A0
FDH047AN08A0	FDP047N08	FDS2734
HUF75639P3	FDS3672	FDP047N10
FDMC2674	FDP5800	FDB047N10
FDB3502	FDS5672	FDD10AN06A0
FDS5672_F095	FDD3860	FDP047AN08A0_G
FDB070AN06A0	HUF75631S3ST	FDI025N06
FDP2572	FDP030N06	HUF76629D3ST
HUFA76429D3	FDP2710	HUF75545P3
FDP3632_G	FDP032N08	RFP12N10L
HUF75645P3_SB82282	FDD2572	FDP050AN06A0
FDP16AN08A0	FDB3652	HUF75639G3
FDB3860	HUF75639S3ST	FDS3692
RFD3055LE	FDD16AN08A0	FDB3632_F101
FDD3672	FDP3672	FDB2532
FDP047AN08A0	PCF75307W_R4903	FDP100N10
FDP3682	FDP047N08V_F102	HUF75852G3
FDB045AN08A0	RFD14N05LSM9A	FDMC2610
FDB060AN08A0	HUF75842P3	FDD3682
FDS2582	FDP120N10	FDP2552
HUF75645S3ST_F101	FDB024N06	RFD14N05LSM
FDP42AN15A0	FDB120N10	FDB150N10
FDP150N10	FDMS2734	FDP060AN08A0
FDMS5672	FDMS3572	RFD16N06LESM9A
FDS2672	FDS2572	FDB035AN06A0
HUF76609D3ST	FDB2614	FDD120AN15A0
FDP038AN06A0_F102	HUF75652G3	FDS3572

Affected Product(s):

FDB2552	FDMS3672	FDB031N08
FDP090N10	FDP3652	FDB13AN06A0
FDD2582	RFD14N05L	FDS3992
FDPF3860T	PCF045AN08W_R4800	FDB3682
FDB029N06	HUF75639S3	FDP025N06
FDA032N08	FDB039N06	FDP2614
RFD16N05LSM9A	FDMS3662	FDP2532
FDPF2710T		

Qualification Plan	Device	Package	Process	No. of Lots
Q20100655	FDB047N10	TO-263	PT3 MV	2

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	245C, 3 cycles	JESD22-A113		0/308
Power cycle	Delta 100C, 3.5 Min cycle	MIL-STD-750-1036	8572cycles	0/154
Temperature Humidity Biased Test	85C, 85%RH, 80V	JESD22-A101	1000 hrs	0/154
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/154
High Temperature Reverse Bias	175C, BV 80%	JESD22-A108	1000 hrs	0/154
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/154
High Temperature Gate Bias	175C, Vgs 100%	JESD22-A108	1000 hrs	0/154

Qualification Plan	Device	Package	Process	No. of Lots
Q200100655	FDP047N10	TO-220	PT3 MV	1

Test Description:	Condition:	Standard :	Duration:	Results:
Power cycle	Delta 100C, 3.5 Min cycle	MIL-STD-750-1036	8572cycles	0/77
Temperature Humidity Biased Test	85C, 85%RH, 80V	JESD22-A101	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Reverse Bias	175C, BV 80%	JESD22-A108	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
High Temperature Gate Bias	175C, Vgs 100%	JESD22-A108	1000 hrs	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20100649	FDB088N08	TO-263	PT3 MV	3

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Gate Bias	175C, 100% Rated VGS	JESD22-A108	1000 hrs	0/231
High Temperature Reverse Bias	175C, 80% Rated BV	JESD22-A108	1000 hrs	0/231

Qualification Plan	Device	Package	Process	No. of Lots
Q20100654	FDP090N10_SW82211	TO-220	PT3 MV	1

Test Description:	Condition:	Standard :	Duration:	Results:
Power cycle	Delta 100C, 3.5 Min cycle	MIL-STD-750-1036	8572cycles	0/77
Temperature Humidity Biased Test	85C, 85%RH, 80V	JESD22-A101	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Reverse Bias	175C, BV 80%	JESD22-A108	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
High Temperature Gate Bias	175C, Vgs 100%	JESD22-A108	1000 hrs	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20100654	FDPF3860	TO-220	PT3 MV	1

Test Description:	Condition:	Standard :	Duration:	Results:
Power cycle	Delta 100C, 3.5 Min cycle	MIL-STD-750-1036	8572cycles	0/77
Temperature Humidity Biased Test	85C, 85%RH, 80V	JESD22-A101	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Reverse Bias	150C, BV 80%	JESD22-A108	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
High Temperature Gate Bias	150C, Vgs 100%	JESD22-A108	1000 hrs	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20100645	FDP025N06	TO-220	PT3 MV	1

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Reverse Bias	175C, BV 80%	JESD22-A108	1000 hrs	0/77
High Temperature Gate Bias	175C, Vgs 100%	JESD22-A108	1000 hrs	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20110266	RFP30N06LE	TO-220	UFET planar	1

Test Description:	Condition:	Standard :	Duration:	Results:
Power cycle	Delta 100C, 3.5 Min cycle	MIL-STD-750-1036	8572cycles	0/77
Temperature Humidity Biased Test	85C, 85%RH, 80V	JESD22-A101	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Reverse Bias	175C, BV 80%	JESD22-A108	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
High Temperature Gate Bias	175C, Vgs 100%	JESD22-A108	1000 hrs	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20110266	RFD16N05LSM9A	TO-220	UFET Planar	2

Test Description:	Condition:	Standard :	Duration:	Results:
Power cycle	Delta 100C, 3.5 Min cycle	MIL-STD-750-1036	8572cycles	0/154
Temperature Humidity Biased Test	85C, 85%RH, 80V	JESD22-A101	1000 hrs	0/154
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/154
High Temperature Reverse Bias	150C, BV 80%	JESD22-A108	1000 hrs	0/154
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/154
High Temperature Gate Bias	150C, Vgs 100%	JESD22-A108	1000 hrs	0/154

Qualification Plan	Device	Package	Process	No. of Lots
Q20100418	FDS2572	SO8	UFET Trench	3

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/462
Power cycle	Delta 100C, 2 Min cycle	MIL-STD-750-1036	10000cycles	0/231
Highly Accelerated Stress Test	130C, 85%RH, 80% VDS	JESD22-A110	96 hrs	0/231
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/231
High Temperature Gate Bias	150C, 100% VGS	JESD22-A108	1000 hrs	0/231
High Temperature Reverse Bias	150C, 80% VDS	JESD22-A108	1000 hrs	0/231
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/231

Qualification Data REPORT

Qualification Plan	Device	Package	Process	No. of Lots
Q20110268B	HUF75545S3S	TO-263	UFET Planar	2

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	245C, 3 cycles	JESD22-A113		0/308
Power cycle	Delta 100C, 3.5 Min cycle	MIL-STD-750-1036	8572cycles	0/154
Temperature Humidity Biased Test	85C, 85%RH, 80V	JESD22-A101	1000 hrs	0/154
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/154
High Temperature Reverse Bias	175C, BV 80%	JESD22-A108	1000 hrs	0/154
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/154
High Temperature Gate Bias	175C, Vgs 100%	JESD22-A108	1000 hrs	0/154

Qualification Plan	Device	Package	Process	No. of Lots
Q20110268B	HUF75645S3ST	TO-263	UFET Planar	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	245C, 3 cycles	JESD22-A113		0/154
Power cycle	Delta 100C, 3.5 Min cycle	MIL-STD-750-1036	8572cycles	0/77
Temperature Humidity Biased Test	85C, 85%RH, 80V	JESD22-A101	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Reverse Bias	175C, BV 80%	JESD22-A108	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
High Temperature Gate Bias	175C, Vgs 100%	JESD22-A108	1000 hrs	0/77

Qualification Data REPORT

Qualification Plan	Device	Package	Process	No. of Lots
Q20110264	FDB088N08	TO-263	UFET Trench	1

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Gate Bias	175C, 100% Rated VGS	JESD22-A108	1000 hrs	0/77
High Temperature Reverse Bias	175C, 80% Rated BV	JESD22-A108	1000 hrs	0/77

Qualification Data REPORT

Qualification Plan	Device	Package	Process	No. of Lots
Q20110199	FDMS2672	MLP	UFET Trench	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/154
Power cycle	Delta 100C, 2 Min cycle	MIL-STD-750-1036	10000cycles	0/77
Highly Accelerated Stress Test	130C, 85%RH, 80% VDS	JESD22-A110	96 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Gate Bias	150C, 100% VGS	JESD22-A108	1000 hrs	0/77
High Temperature Reverse Bias	150C, 80% VDS	JESD22-A108	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20110199	FDS2734	SO8	UFET Trench	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/154
Power cycle	Delta 100C, 2 Min cycle	MIL-STD-750-1036	10000cycles	0/77
Highly Accelerated Stress Test	130C, 85%RH, 80% VDS	JESD22-A110	96 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Gate Bias	150C, 100% VGS	JESD22-A108	1000 hrs	0/77
High Temperature Reverse Bias	150C, 80% VDS	JESD22-A108	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Data REPORT

Qualification Plan	Device	Package	Process	No. of Lots
Q20110270A	FDB2614	TO-263	UFET Trench	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	245C, 3 cycles	JESD22-A113		0/154
Power cycle	Delta 100C, 3.5 Min cycle	MIL-STD-750-1036	8572cycles	0/77
Temperature Humidity Biased Test	85C, 85%RH, 80V	JESD22-A101	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
High Temperature Reverse Bias	150C, BV 80%	JESD22-A108	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
High Temperature Gate Bias	150C, Vgs 100%	JESD22-A108	1000 hrs	0/77